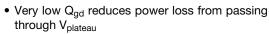


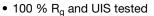
N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	$R_{DS(on)}$ (Ω) MAX.	I _D (A)	Q _g (TYP.)	
80	0.0077at V _{GS} = 10 V	90	80	
	0.0080 at $V_{GS} = 7.5 \text{ V}$	96	00	

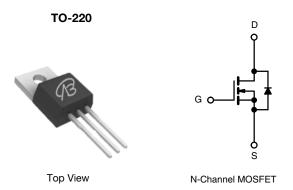
FEATURES

- Trench power MOSFET
- Maximum 175 °C junction temperature









APPLICATIONS

- Power supply
 - Secondary synchronous rectification
- DC/DC converter
- Power tools
- · Motor drive switch
- DC/AC inverter
- Battery management

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	80	V		
Gate-Source Voltage	V _{GS}	± 20	V		
Continuous Dunis Comment (T. 150 °C)	T _C = 25 °C	,	90		
Continuous Drain Current (T _J = 150 °C)	T _C = 70 °C	I _D	72 ^d	^	
Pulsed Drain Current (t = 100 μs)	I _{DM}	270	A		
Avalanche Current		I _{AS}	70		
Single Avalanche Energy ^a	L = 0.1 mH	E _{AS}	240	mJ	
Maximum Davier Dissination 8	T _C = 25 °C	D	370 ^b	14/	
Maximum Power Dissipation ^a	T _C = 125 °C	P _D	121 b	W	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +175	°C	

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	LIMIT	UNIT		
Junction-to-Ambient (PCB Mount) ^c	R _{thJA}	40	°C/W		
Junction-to-Case (Drain)	R _{thJC}	0.4			

Notes

- a. Duty cycle \leq 1 %.
- b. See SOA curve for voltage derating.
- c. When mounted on 1" square PCB (FR4 material).
- d. Package limited.

服务热线:400-655-8788

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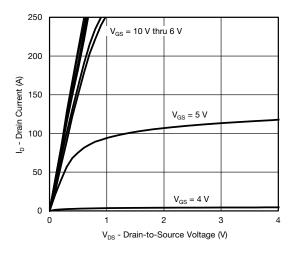
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	80	-	-	V
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	-	4	
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 250	nA
		V _{DS} = 80 V, V _{GS} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V, V _{GS} = 0 V, T _J = 125 °C	-	-	150	μA
		V _{DS} = 80 V, V _{GS} = 0 V, T _J = 175 °C	-	-	5	mA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	120	-	-	Α
Drain Course On State Resistance 2	Ь	V _{GS} = 10 V, I _D = 30 A	-	0.0077	-	0
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 7.5 V, I _D = 20 A	-	0.0080	-	Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A	-	82	-	S
Dynamic ^b			•	•		
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 40 V, f = 1 MHz	-	6200	-	pF
Output Capacitance	C _{oss}		-	3200	-	
Reverse Transfer Capacitance	C _{rss}		-	348	-	
Total Gate Charge ^c	Qg		-	94	141	
Gate-Source Charge ^c	Q_{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	-	31	-	nC
Gate-Drain Charge ^c	Q_{gd}		-	10	-	
Gate Resistance	R_g	f = 1 MHz	0.28	1.4	2.8	Ω
Turn-On Delay Time °	t _{d(on)}		-	24	40	
Rise Time ^c	t _r	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$	-	24	40	
Turn-Off Delay Time ^c	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	34	60	ns
Fall Time ^c	t _f		-	14	28	
Drain-Source Body Diode Ratings ar	nd Characteris	stics ^b (T _C = 25 °C)	•	•		
Pulsed Current (t = 100 μs)	I _{SM}		-	-	270	Α
Forward Voltage ^a	V_{SD}	I _F = 10 A, V _{GS} = 0 V	-	0.8	1.5	V
Reverse Recovery Time	t _{rr}		-	15	-	ns
Peak Reverse Recovery Charge	I _{RM(REC)}	$I_F = 34 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	-	5	10	Α
Reverse Recovery Charge	Q _{rr}		-	0.315	0.475	μC

Notes

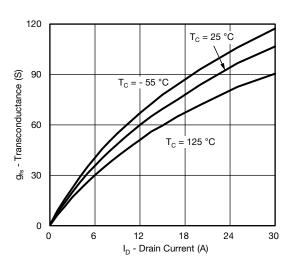
- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing. c. Independent of operating temperature.



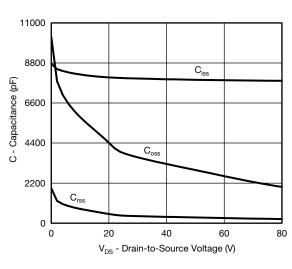
TYPICAL CHARACTERISTICS ($T_A = 25$ °C, unless otherwise noted)



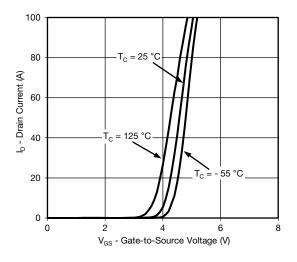
Output Characteristics



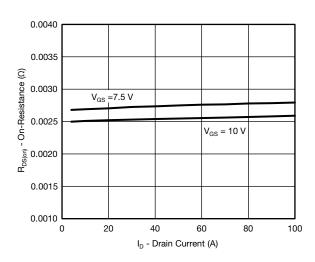
Transconductance



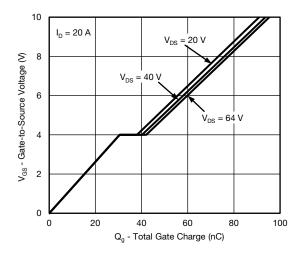
Capacitance



Transfer Characteristics



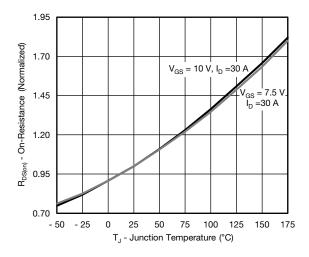
On-Resistance vs. Drain Current



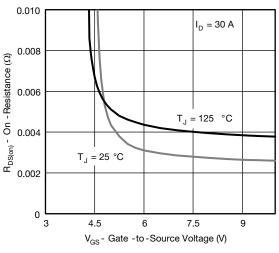
Gate Charge



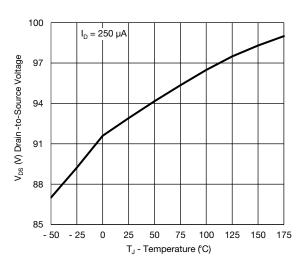
TYPICAL CHARACTERISTICS (T_A = 25 °C, unless otherwise noted)



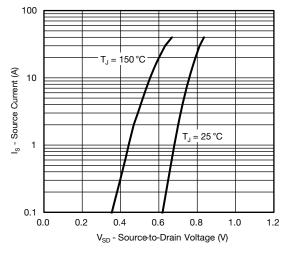
On-Resistance vs. Junction Temperature



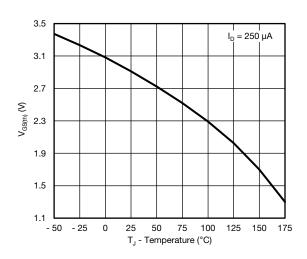
On-Resistance vs. Gate-to-Source Voltage



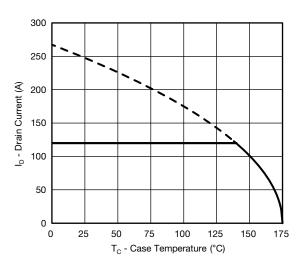
Drain Source Breakdown vs. Junction Temperature



Source Drain Diode Forward Voltage



Threshold Voltage

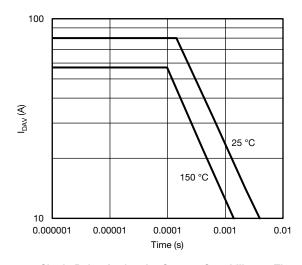


Current De-rating



5

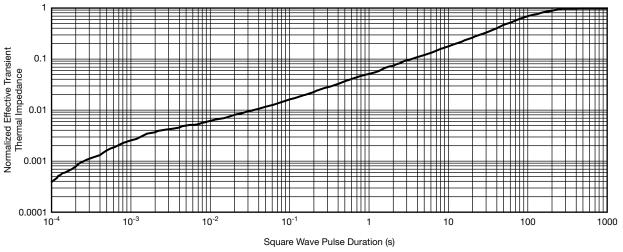
THERMAL RATINGS ($T_A = 25$ °C, unless otherwise noted)



1000 I_{DM} Limited 10 µs 100 I_D - Drain Current (A) 100 μs 10 Limited by Bsid 1 1 ms 111111 0.1 T_C = 25°C Single Pulse 10 ms **BVDSS** Limited 0.01 $\begin{array}{cc} & 1 & 10 \\ V_{DS}\text{-} Drain-to-Source Voltage (V) \\ ^*V_{GS}> minimum \ V_{GS} \ at \ which \ R_{DS(on)} \ is \ specified \end{array}$ 0.1 100

Single Pulse Avalanche Current Capability vs. Time

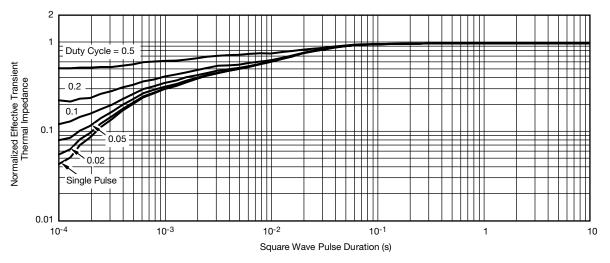




Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS (T_A = 25 °C, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

Note

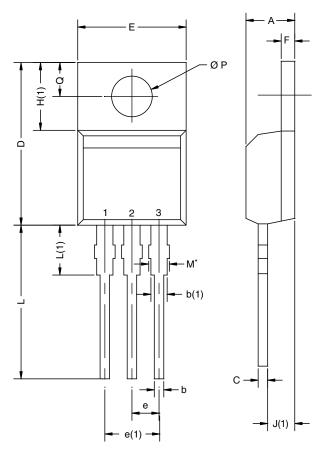
- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction to Ambient (25 °C)

can widely vary depending on actual application parameters and operating conditions.

- Normalized Transient Thermal Impedance Junction to Case (25 °C) are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities



TO-220AB



	D2

	MILLIMETERS		INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
D2	12.19	12.70	0.480	0.500
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØΡ	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471				

Note

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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